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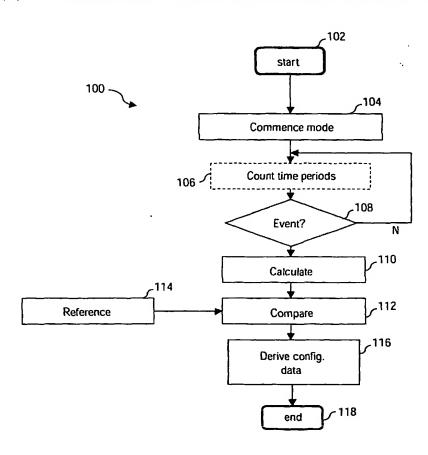
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(54) Title: OBTAINING CONFIGURATION DATA FOR A DATA PROCESSING APPARATUS

(57) Abstract: A method to obtain configuration data for a data processing apparatus by calculating (110) a time interval between the commencement of a mode (104) and a subsequent event (108). The calculated time interval is then compared (112) with one or more reference values (114). The result of the comparison is used to derive configuration data (116). The method may be further refined by including a calibration stage to reduce the error in the calculated time interval, thereby allowing comparison with a larger set of reference values (114), which in turn permits more configuration data to be derived from the calculated time interval.

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